

Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 12732-061002	Application No. New Divisional Application <i>10/192132</i>	
Information Disclosure Statement by Applicant (Use several sheets if necessary)				Applicant Taketomi Asami et al.		
(37 CFR §1.98(b))				Filing Date March 4, 2004	Group Art Unit <i>2818</i>	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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Examiner Signature

JOSEPH NEVREN

Date Considered

1/19/05

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
SN	ABB	6,690,068	02/10/2004	Yamazaki et al.			

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Sheet 1 of 1

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-061002	Application No. 10/792,132
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Taketomi Asami et al.	
(37 CFR §1.98(b))		Filing Date March 4, 2004	Group Art Unit 2815

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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	AK						

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Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
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	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

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	AS	
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